

N THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:

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MEHDI

Assignee:

KLA-TENCOR TECHNOLOGIES CORPORATION

Title:

SYSTEM AND METHODS FOR A WAFER INSPECTION SYSTEM

USING MULTIPLE ANGLES AND MULTIPLE WAVELENGTH

ILLUMINATION

Serial No.:

09/891,693

Filing Date:

June 26, 2001

Examiner:

Hoa Q. Pham

Group Art Unit:

2877

Docket No.:

M-10693 US

San Francisco, California February 27, 2003

BOX DAC COMMISSIONER FOR PATENTS Washington, DC 20231

RESPONSE TO OFFICE ACTION

RECEIVED

MAR 0 7 2003

OFFICE OF PETITIONS

Dear Sir:

This responds to the Office Action mailed on January 24, 2002, setting a period for response expiring on April 24, 2002. A Petition for Extension of Time to extend the response period to expire on July 24, 2002, was submitted together with this response on July 24, 2002. However, the application serial number was incorrectly entered on the Response documents as 09/298,007, thus, resulting in this Petition To Revive.

IN THE SPECIFICATION

On page 9, paragraph 33, line 5, please add after "channel 420." the following: -- In other words, illumination channel 416 is at around zero degrees to a normal direction to surface 426. -- The fully amended paragraph is attached hereto.

03/07/2003 AMENDAF1 D0000088 09891693

03 FC:1201 04 FC:1202 05 FC:1451 252.00 OP 648.00 OP

Serial No. 09/891,693